

FDJ127P

P-Channel -1.8 Vgs Specified PowerTrench® MOSFET

General Description

This P-Channel -1.8V specified MOSFET uses Fairchild's advanced low voltage Power Trench process. It has been optimized for battery power management applications.

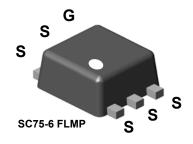
Applications

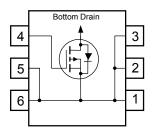
- · Battery management
- · Load switch

Features

• -4.1 A, -20 V. $R_{DS(ON)} = 60 \text{ m}\Omega$ @ $V_{GS} = -4.5 \text{ V}$ $R_{DS(ON)} = 85 \text{ m}\Omega$ @ $V_{GS} = -2.5 \text{ V}$ $R_{DS(ON)} = 133 \text{ m}\Omega$ @ $V_{GS} = -1.8 \text{ V}$

- · Low gate charge
- High performance trench technology for extremely low $R_{\mbox{\scriptsize DS(ON)}}$
- Compact industry standard SC75-6 surface mount package





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		-20	V
V _{GSS}	Gate-Source Voltage		± 8	V
I _D	Drain Current - Continuous	(Note 1)	-4.1	Α
	– Pulsed		-16	1
P _D	Power Dissipation	(Note 1)	1.6	W
T_{J}, T_{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	Note 1)	77	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
.C	FDJ127P	7"	8mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics			I	I	ı
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, \qquad I_{D} = -250 \mu\text{A}$	-20			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A,Referenced to 25°C		-12		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -16 \text{ V}, V_{GS} = 0 \text{ V}$			-1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	V_{GS} = 8 V, V_{DS} = 0 V			100	nA
I _{GSSR}	Gate–Body Leakage, Reverse	$V_{GS} = -8 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)				•	•
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	-0.4	-0.8	-1.5	V
$\Delta V_{GS(th)} \over \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I_D = -250 μ A,Referenced to 25°C		3		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	V _{GS} = -4.5 V, I _D = -4.1 A V _{GS} = -2.5 V, I _D = -3.5 A V _{GS} = -1.8 V, I _D = -2.7 A V _{GS} = -4.5 V, I _D = -4.1,T _J =125°C		42 61 97 60	60 85 133	mΩ
I _{D(on)}	On-State Drain Current	$V_{GS} = -4.5 \text{ V}, I_D = -4.1, T_J = 125^{\circ}\text{C}$ $V_{GS} = -4.5 \text{ V}, V_{DS} = -5 \text{ V}$	-16			Α
g _{FS}	Forward Transconductance	$V_{DS} = -5 \text{ V}, I_{D} = -4.1 \text{ A}$		10		S
Dynamic Ch	naracteristics					•
C _{iss}	Input Capacitance	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$		780		pF
C _{oss}	Output Capacitance	f = 1.0 MHz		120		pF
C _{rss}	Reverse Transfer Capacitance			60		pF
Switching C	characteristics (Note 2)					
d(on)	Turn-On Delay Time	$V_{DD} = -10 \text{ V}, I_D = -1 \text{ A},$		10	20	ns
r	Turn-On Rise Time	$V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$		9	10	ns
d(off)	Turn-Off Delay Time			27	43	ns
f	Turn-Off Fall Time			11	20	ns
Q_g	Total Gate Charge	$V_{DS} = -10 \text{ V}, I_{D} = -4.1 \text{ A},$		7.2	10	nC
Q_{gs}	Gate-Source Charge	V _{GS} = -4.5 V		1.7		nC
Q_{gd}	Gate-Drain Charge	<u></u>		1.5		nC
Drain-S	ource Diode Characteristics	and Maximum Ratings				
l _s	Maximum Continuous Drain–Source				-2.5	Α
V _{SD}	Drain–Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = -2.5 \text{ A} \text{(Note 2)}$		-0.8	-1.2	V

Notes:

1. R_{0JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{0JC} is guaranteed by design while R_{0CA} is determined by the <u>user's board design</u>



a) 77°C/W when mounted on a 1in² pad of 2 oz copper.



o) 110°C/W when mounted on a minimum pad of 2 oz copper.

Scale 1:1 on letter size paper

2. Pulse Test: Pulse Width < 300μ s, Duty Cycle < 2.0%

Typical Characteristics

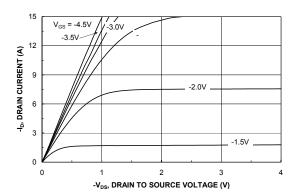


Figure 1. On-Region Characteristics.

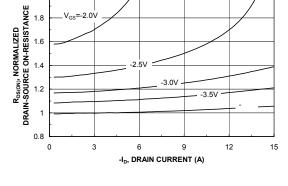


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

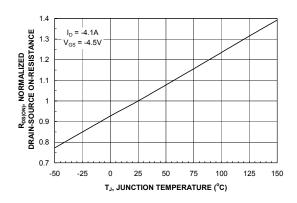


Figure 3. On-Resistance Variation withTemperature.

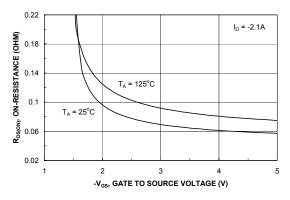


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

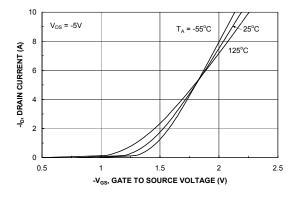


Figure 5. Transfer Characteristics.

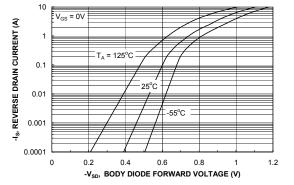
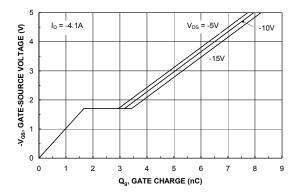


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



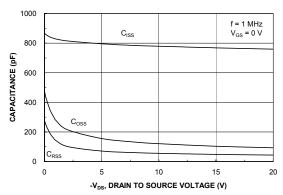


Figure 7. Gate Charge Characteristics.

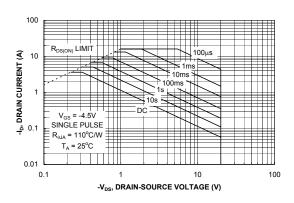


Figure 8. Capacitance Characteristics.

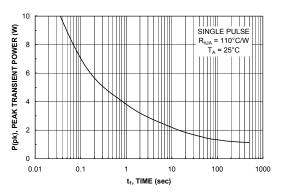


Figure 9. Maximum Safe Operating Area.



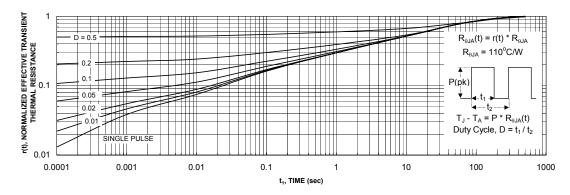


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1. Transient thermal response will change depending on the circuit board design.

TRADEMARKS

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

$ACEx^{TM}$	FAST®	ISOPLANAR™	Power247™	SuperFET™
ActiveArray™	FASTr™	LittleFET™	PowerSaver™	SuperSOT™-3
Bottomless™	FPS™	$MICROCOUPLER^{TM}$	PowerTrench®	SuperSOT™-6
CoolFET™	FRFET™	MicroFET™	QFET®	SuperSOT™-8
$CROSSVOLT^{\text{TM}}$	GlobalOptoisolator™	MicroPak™	QS^{TM}	SyncFET™
DOME™	GTO™ .	MICROWIRE™	QT Optoelectronics™	TinyLogic [®]
EcoSPARK™	HiSeC™	MSX TM	Quiet Series™	TINYOPTO™
E ² CMOS TM	I ² C TM	MSXPro™	RapidConfigure™	TruTranslation™
EnSigna™	<i>i-</i> Lo [™]	OCX^{TM}	RapidConnect™	UHC™
FACT™	ImpliedDisconnect™	OCXPro™	μSerDes™	UltraFET®
FACT Quiet Serie	es [™]	OPTOLOGIC®	SILENT SWITCHER®	VCX TM
Across the board	d. Around the world.™	OPTOPLANAR™	SMART START™	
The Power France		PACMAN™	SPM TM	
			<u> </u>	

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

POPTM

LIFE SUPPORT POLICY

 $Programmable \ Active \ Droop^{\tiny\mathsf{TM}}$

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

- 1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the
- 2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

Stealth™

PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.

Rev. I11